•	Searcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/659,101	CHAN ET AL.	
Examiner	Art Unit	
Randall Chin	1744	

	SEARCHED		
Class	Subclass	Date	Examiner
15	143.1	1	1
15	167.1	8/1/2005	RC
			_

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		 	
	<u> </u>		

SEARCH NO (INCLUDING SEARC		·)
	DATE	EXMR
Inventor name search	8/1/2005	RC
,		